

FOURIER TRANSFORM ANALYSIS: (1) X-RAY DIFFRACTION EFFECTS BY FINITE MONTMORILLONITE AND MICA CRYSTALS

by

MALCOLM ROSS

U.S. Geological Survey, Washington, D.C. 20242

ABSTRACT

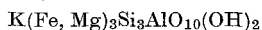
A COMPUTER program has been developed to generate the X-ray diffraction intensity distribution along any particular reciprocal lattice row, plane, or volume, for any arbitrary group of atoms within a crystal. The program, which maps the intensity in crystal reciprocal space in much the same way as a conventional Fourier series program maps the electron density in direct crystal space, has been used to calculate the expected X-ray diffraction line profiles for a number of montmorillonite and mica crystallites of varying thicknesses in the c^* direction.

The program evaluates the function

$$G(HKL) = \sum_{n=1}^N f_n \exp 2\pi i(Hx_n + Ky_n + Lz_n),$$

where $G(HKL)$ is the Fourier transform of an array of N -atoms at a particular H , K , L coordinate in reciprocal space, f_n is the scattering factor of the n th atom, and x , y , z its coordinates in direct space. The function is evaluated for all N -atoms within the finite model crystal under study for non-integral as well as integral values of H , K , and L . In practice a complete line profile is made by calculating $G(HKL)$ at intervals in the range of $(100 \text{ \AA})^{-1}$ to $(10,000 \text{ \AA})^{-1}$.

The apparent d -spacings of the various clay mineral models, as given by the line profiles, approach asymptotically the true value as the number of layers increase. For example, the apparent d_{001} spacing for a mica of the composition



is 12.91, 11.35, 10.79, 10.53, 10.38, 10.22, 10.14, 10.04 and 10.02 Å for crystals 2, 3, 4, 5, 6, 8, 10, 20, and 30 layers thick, respectively. For the infinitely thick crystal, $d_{001} = 10.000 \text{ \AA}$. The apparent d_{001} spacing for a montmorillonite of the composition $\text{K}_{0.33}\text{Al}_2(\text{Si, Al})_4\text{O}_{10}(\text{OH})_2 \cdot 4\text{H}_2\text{O}$ (true $d_{001} = 15.400 \text{ \AA}$) is 18.85, 16.80, 15.87, 15.52, and 15.41 Å for crystals 2, 3, 5, 10, and 30 layers thick, respectively.

These diffraction profiles and line shifts can be used in analyzing montmorillonites, micas, and mixed-layer montmorillonite-mica clays.